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SOITEC ADOPTS QCEPT TECHNOLOGIES' NVD INSPECTION SOLUTION FOR SILICON-ON-INSULATOR WAFER PRODUCTION APPLICATIONS

ATLANTA, Ga. – December 4, 2008 – Qcept Technologies Inc., the developer of a new breed of wafer inspection systems for the semiconductor manufacturing industry, announced that Soitec, the leading supplier of silicon-on-insulator (SOI) and other engineered substrates, has adopted its ChemetriQ[®] 3000 non-visual defect (NVD) inspection system after several months of collaborative effort. The ChemetriQ system is installed at Soitec's Bernin II 300-mm SOI production fab, where it is currently being used for incoming quality control of bare silicon wafers and process monitoring of SOI wafers.

To win the order, Qcept's ChemetriQ solution had to meet Soitec's strict return-on-investment and production-worthiness criteria. Following the successful tool evaluation and subsequent order, both parties also agreed to participate in an ongoing SOI application development effort focused on extending the use of Qcept's technology in existing inspection applications, as well as developing new applications, for improving process control, quality and final yield of Soitec's SOI wafers.

"Soitec is committed to providing the highest-quality engineered substrates that the semiconductor industry needs to enable mobile, high-performance and advanced microelectronic applications," stated Christophe Maleville, vice president of the SOI Products Platform at Soitec. "Qcept's ChemetriQ inspection technology offers unique insight into the condition of incoming bare wafers, as well as our own manufacturing process, by enabling us to find potential yield issues that we otherwise couldn't detect. This solution provides an added level of quality assurance for our end products."

"NVDs are an increasing yield concern for wafer and IC manufacturers alike as tighter process tolerances are required and new materials are introduced," stated Erik Smith, president of Qcept Technologies. "We are pleased that Soitec, the world's leading supplier of SOI wafers, has chosen to use our ChemetriQ system to monitor their advanced manufacturing process. This validation, along with our success at major IC manufacturers, is testament to the growing awareness of the need for NVD inspection as part of a total yield management strategy for both wafer and IC fabrication."

Qcept's ChemetriQ platform provides rapid, full-wafer, inline detection of NVDs, such as organic and inorganic residue, metallic contaminants, process-induced charging, watermarks and other non-visual residue defects that are undetectable by optical inspection systems. ChemetriQ accomplishes this by employing an innovative, non-destructive technology that detects work function variations on the surface of semiconductor wafers. The ChemetriQ platform is sensitive to 5E9 atoms/cm² (one atom out of 200,000 per square centimeter), which exceeds the requirements outlined in the International Technology Roadmap for Semiconductors (ITRS) for metallic contamination detection down to the 22-nm node.

About the Soitec Group:

The Soitec Group is the world's leading innovator and provider of the engineered substrate solutions that serve as the foundation for today's most advanced microelectronic products. The group leverages its proprietary Smart Cut[™] technology to engineer new substrate solutions, such as silicon-on-insulator (SOI) wafers, which became the first high-volume application for this proprietary technology. Since then, SOI has emerged as the material platform of the future, enabling the production of higher performing, faster chips that consume less power.

Today, Soitec produces more than 80 percent of the world's SOI wafers. Headquartered in Bernin, France, with two high-volume fabs on-site, Soitec has offices throughout the United States, Japan and Taiwan, and a new production site in the process of customers' qualification in Singapore.

Two other divisions, Picogiga International (Les Ulis) and Tracit Technologies (Bernin), complete the Soitec Group. Picogiga focuses on delivering advanced substrates solutions, including III-Vs epiwafers and gallium nitride (GaN)-based wafers, to the compound material world for the manufacture of high-frequency electronics and other optoelectronic devices. Tracit, on the other hand, focuses on thin-film layer transfer technologies used to manufacture advanced substrates for power ICs and microsystems, as well as generic circuit transfer technology for applications such as image sensors and 3D-integration. Shares of the Soitec Group are listed on Euronext Paris.

About Qcept Technologies Inc.:

Qcept delivers wafer inspection solutions for non-visual defect (NVD) detection in advanced semiconductor manufacturing. Qcept's ChemetriQ® platform is being adopted in critical processes for inline, non-contact, full-wafer detection of such NVDs as sub-monolayer organic and metallic residues, process-induced charging, and other undesired surface non-uniformities that cannot be detected by conventional optical inspection equipment. More information can be found at www.qceptech.com.

ChemetriQ is a registered trademark of Qcept Technologies Inc. All other trademarks are the property of their respective owners.

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